NXP BLF8G24LS-150V 8G24LS-150GV 24LS-100GV transistor datasheet

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230 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 1800 MHz to 2000 MHz.

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BLF8G24LS-150V; BLF8G24LS-150GV

Power LDMOS transistor

Rev. 2 — 24 February 2014

Objective data sheet

1. Product profile

1.1 General description

150 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2300 MHz to 2400 MHz.

Table 1. Typical performance

Typical RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

Test signal	f	I _{Dq}	V_{DS}	P _{L(AV)}	Gp	η_D	ACPR _{5M}
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	2300 to 2400	1300	28	45	18	30	-30 <mark>[1]</mark>

[1] 3GPP test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on CCDF; carrier spacing 5 MHz. Channel bandwidth is 3.84 MHz.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low thermal resistance providing excellent thermal stability
- Decoupling leads to enable improved video bandwidth (70 MHz typical)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent digital pre-distortion capability
- Internally matched for ease of use
- Integrated ESD protection
- Design optimized for gull-wing
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

 RF power amplifiers for base stations and multi carrier applications in the 2300 MHz to 2400 MHz frequency range



2. Pinning information

Pin	Description	Simplified outline	Graphic symbol
BLF8G24I	_S-150V (SOT1244B)		
1	drain		
2	gate	4 1 5	6 7 → I → 4,5
3	source		
1	decoupling lead	3	2 1 1
5	decoupling lead		aaa-003619
6	n.c.		
7	n.c.	6 2 7	
BLF8G24I	_S-150GV (SOT1244C))	
1	drain		
2	gate		6 7 → 1 → 4,5
3	source		
1	decoupling lead		2
5	decoupling lead		aaa-003619
6	n.c.	6 2 7 3	
7	n.c.		

3. Ordering information

Table 3. Ordering information			
Type number Package			
	Name	Description	Version
BLF8G24LS-150V	-	earless flanged ceramic package; 6 leads	SOT1244B
BLF8G24LS-150GV	-	earless flanged ceramic package; 6 leads	SOT1244C

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage		-	65	V
V _{GS}	gate-source voltage		-0.5	+13	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		<u>[1]</u> -	225	°C

[1] Continuous use at maximum temperature will affect the reliability, for details refer to the on-line MTF calculator.

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5. Thermal characteristics

Table 5.	Thermal characteristics			
Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-c)}	thermal resistance from junction to case	$T_{case} = 80 \ ^{\circ}C; P_{L} = 45 \ W$	0.30	K/W

6. Characteristics

Table 6. DC characteristics

$T_j = 25 ^{\circ}C$ unless otherwise specified.						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	V_{GS} = 0 V; I_D = 2.16 mA	65	-	-	V
V _{GS(th)}	gate-source threshold voltage	V_{DS} = 10 V; I_{D} = 216 mA	1.5	1.9	2.3	V
V_{GSq}	gate-source quiescent voltage	V_{DS} = 28 V; I_{D} = 1300 mA	1.6	2	2.4	V
I _{DSS}	drain leakage current	V_{GS} = 0 V; V_{DS} = 28 V	-	-	4.5	μA
I _{DSX}	drain cut-off current	$\label{eq:VGS} \begin{array}{l} V_{GS} = V_{GS(th)} + 3.75 \; V; \\ V_{DS} = 10 \; V \end{array}$	-	40	-	A
I _{GSS}	gate leakage current	V_{GS} = 11 V; V_{DS} = 0 V	-	-	450	nA
9 _{fs}	forward transconductance	V_{DS} = 10 V; I _D = 10.8 A	-	16	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 V;$ $I_D = 7.56 A$	-	0.06	-	Ω

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA; 3GPP test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on the CCDF, carrier spacing 5 MHz; $f_1 = 2302.5$ MHz; $f_2 = 2307.5$ MHz; $f_3 = 2392.5$ MHz; $f_4 = 2397.5$ MHz; RF performance at $V_{DS} = 28$ V; $I_{Dq} = 1300$ mA; $T_{case} = 25$ °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L(AV)} = 45 \text{ W}$	<tbd></tbd>	18	-	dB
RL _{in}	input return loss	$P_{L(AV)} = 45 \text{ W}$	-	-10	<tbd></tbd>	dB
η_D	drain efficiency	$P_{L(AV)} = 45 \text{ W}$	<tbd></tbd>	30	-	%
$ACPR_{5M}$	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 45 \text{ W}$	-	-30	<tbd></tbd>	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G24LS-150V and BLF8G24LS-150GV are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dq} = 1300 mA; P_L = 150 W (CW); f = 2300 MHz.

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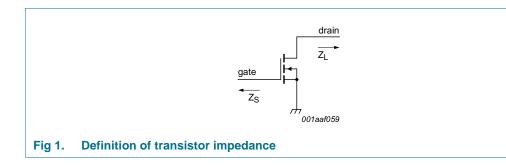
7.2 Impedance information

Table 8.Typical impedance

Measured load-pull data;	$I_{Dq} = 1300 \text{ mA};$	$V_{DS} = 28 V.$
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BLF8G24LS-150V 2300 1.25 – j4.11 2.95 – j1.20 2400 2.34 – j5.50 2.88 – j1.31 2500 5.65 – j6.35 2.80 – j1.35 BLF8G24LS-150GV 2300 1.29 – j5.78 3.13 – j3.26 2400 2.15 – j7.09 2.78 – j3.44	Dy		
BLF8G24LS-150V 2300 1.25 – j4.11 2.95 – j1.20 2400 2.34 – j5.50 2.88 – j1.31 2500 5.65 – j6.35 2.80 – j1.35 BLF8G24LS-150GV 2300 1.29 – j5.78 3.13 – j3.26 2400 2.15 – j7.09 2.78 – j3.44	f	Z _S [1]	Z _L [1]
2300 1.25 - j4.11 2.95 - j1.20 2400 2.34 - j5.50 2.88 - j1.31 2500 5.65 - j6.35 2.80 - j1.35 BLF8G24LS-150GV 2300 1.29 - j5.78 3.13 - j3.26 2400 2.15 - j7.09 2.78 - j3.44	(MHz)	(Ω)	(Ω)
2400 2.34 - j5.50 2.88 - j1.31 2500 5.65 - j6.35 2.80 - j1.35 BLF8G24LS-150GV 2300 1.29 - j5.78 3.13 - j3.26 2400 2.15 - j7.09 2.78 - j3.44	BLF8G24LS-150V		
2500 5.65 - j6.35 2.80 - j1.35 BLF8G24LS-150GV 2300 1.29 - j5.78 3.13 - j3.26 2400 2.15 - j7.09 2.78 - j3.44	2300	1.25 – j4.11	2.95 – j1.20
BLF8G24LS-150GV 3.13 - j3.26 2300 1.29 - j5.78 3.13 - j3.26 2400 2.15 - j7.09 2.78 - j3.44	2400	2.34 – j5.50	2.88 – j1.31
2300 1.29 - j5.78 3.13 - j3.26 2400 2.15 - j7.09 2.78 - j3.44	2500	5.65 – j6.35	2.80 – j1.35
2400 2.15 – j7.09 2.78 – j3.44	BLF8G24LS-150GV		
	2300	1.29 – j5.78	3.13 – j3.26
2500 6.61 – j7.57 2.98 – j3.66	2400	2.15 – j7.09	2.78 – j3.44
	2500	6.61 – j7.57	2.98 – j3.66

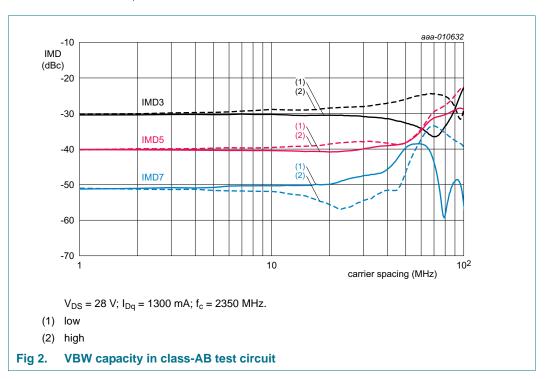
[1] Z_S and Z_L defined in Figure 1.



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7.3 VBW in a class-AB operation

The BLF8G24LS-150V shows 70 MHz (typical) video bandwidth (IMD third-order intermodulation inflection point) in a class-AB test circuit in the 2.3 GHz to 2.4 GHz band at V_{DS} = 28 V and I_{Dq} = 1.3 A.



7.4 Test circuit

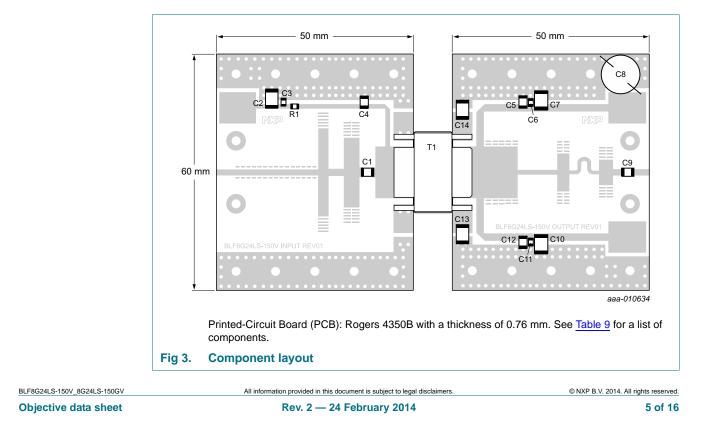


Table 9. List of components

See Figure 3 for component layout.

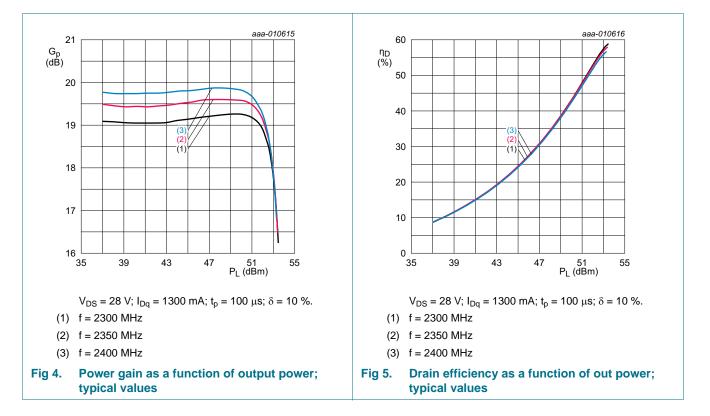
Component	Description	Value		Remarks
C1	multilayer ceramic chip capacitor	1.2 pF	[1]	ATC 800B
C2	multilayer ceramic chip capacitor	1 μF	[2]	Murata
C3	multilayer ceramic chip capacitor	100 nF	[2]	Murata
C4, C5, C9, C12	multilayer ceramic chip capacitor	24 pF	[1]	ATC 800B
C6, C11	multilayer ceramic chip capacitor	220 nF	[2]	Murata
C7, C10, C13, C14	multilayer ceramic chip capacitor	4.7 μF, 50 V	[2]	Murata
C8	electrolytic capacitor	> 470 µF, 63 V		
R1	chip resistor	4.7 Ω, 1 % tolerance		SMD 0805
T1	transistor	-		NXP BLF8G24LS-150V

[1] American Technical Ceramics type 800B or capacitor of same quality.

[2] Murata or capacitor of same quality.

7.5 Graphical data

7.5.1 Pulsed CW



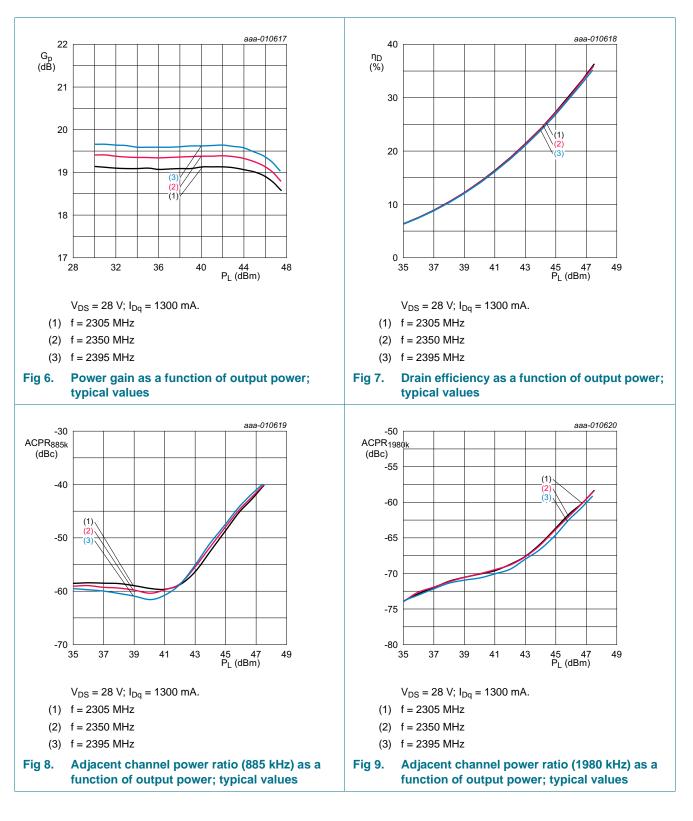
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7.5.2 IS-95

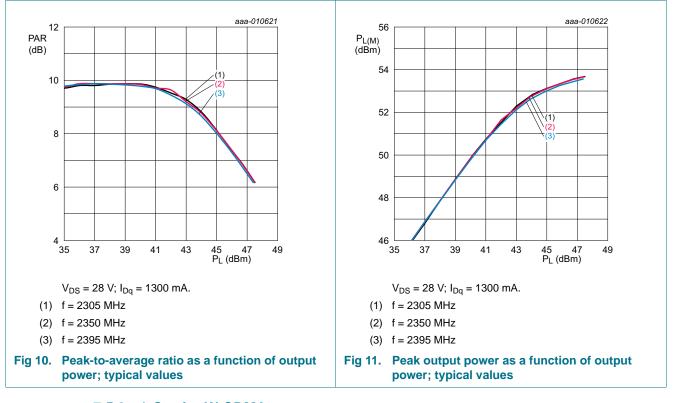


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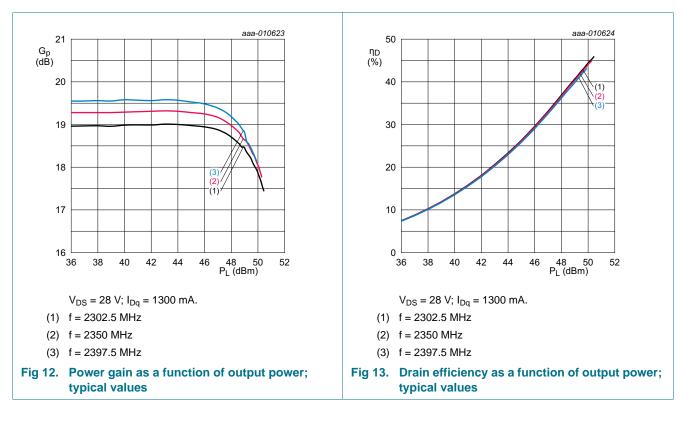
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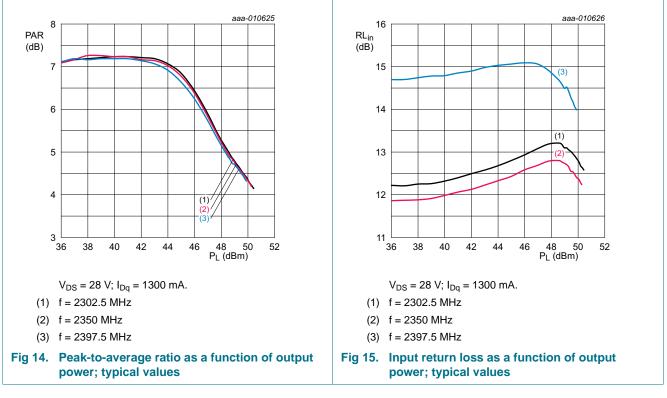




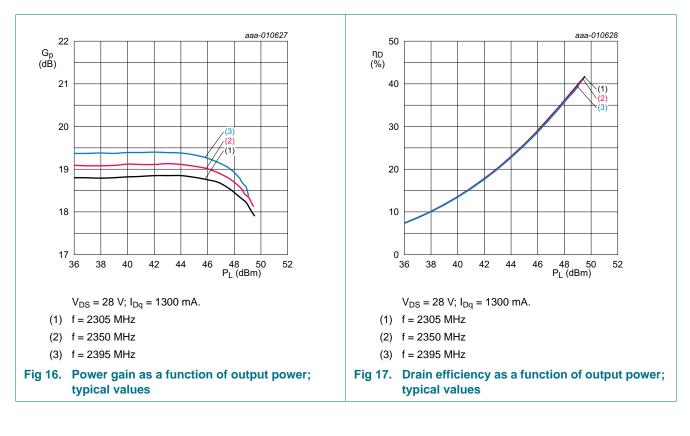
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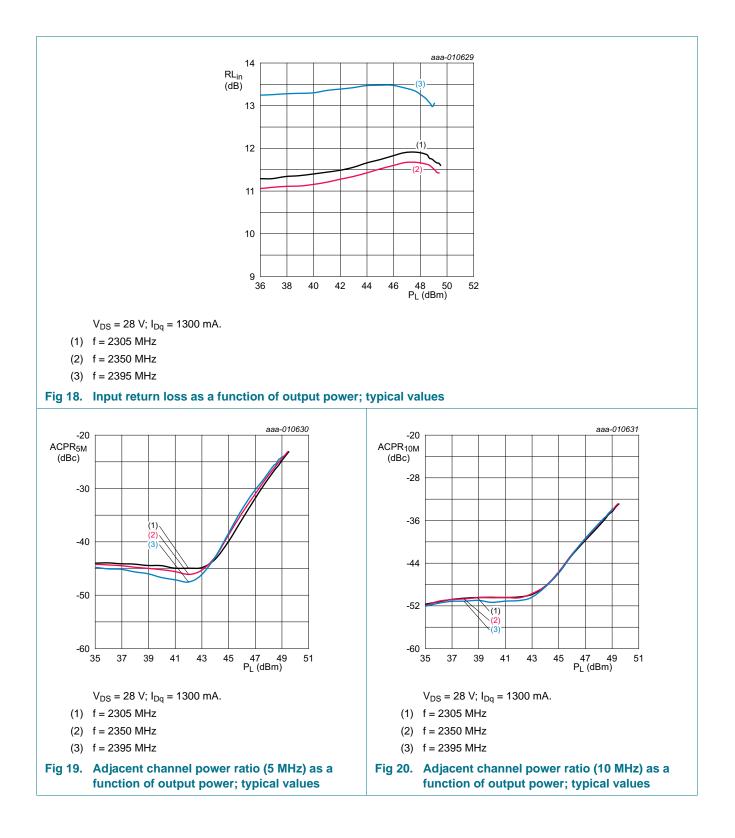




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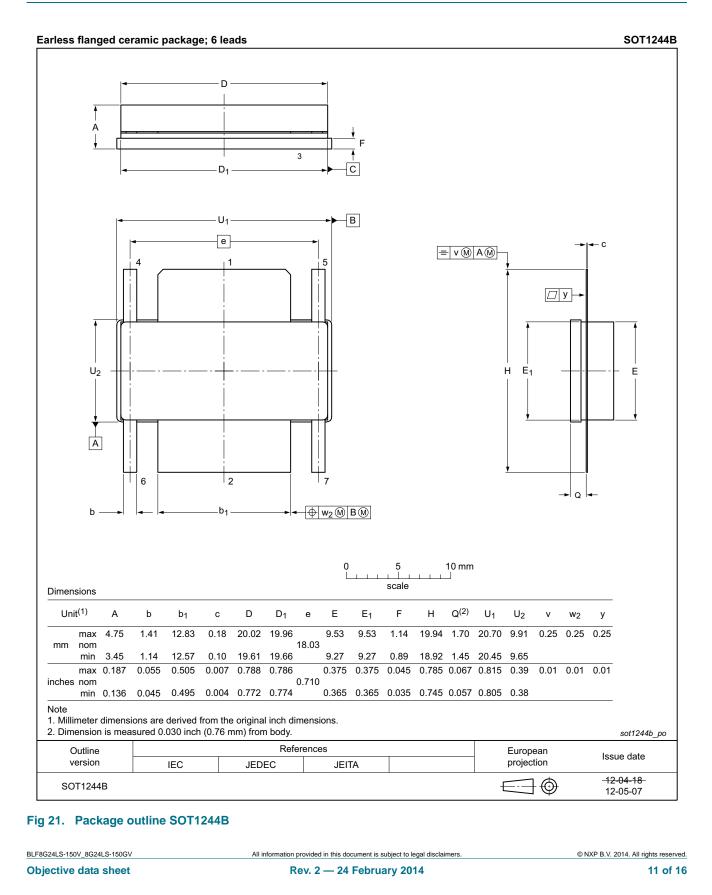
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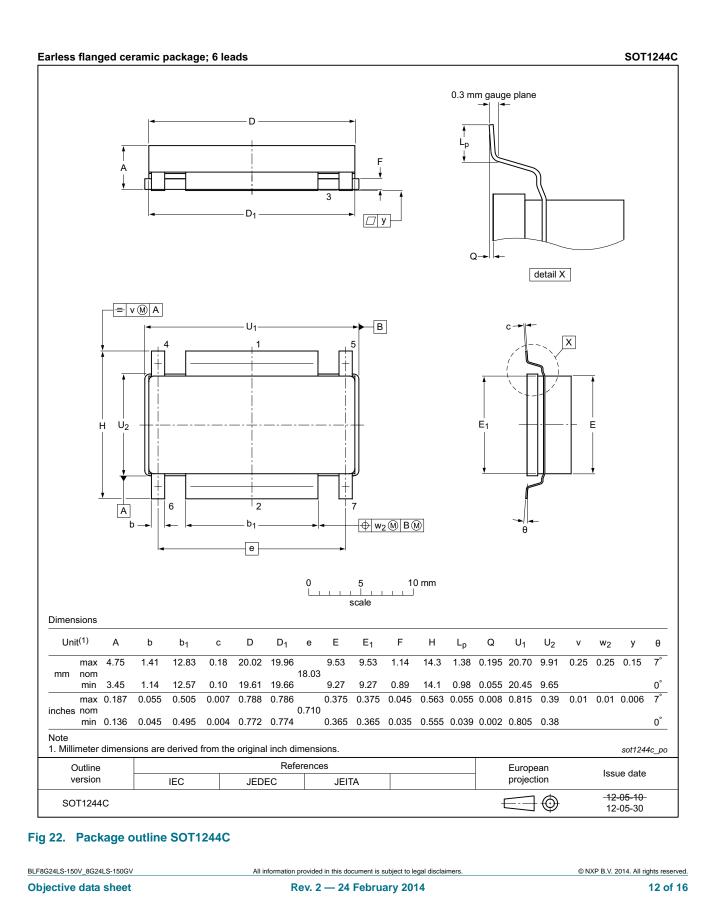
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8. Package outline





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Handling information 9.

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10.	Abbreviations
Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
IS-95	Interim Standard 95
LDMOS	Laterally Diffused Metal Oxide Semiconductor
MTF	Median Time to Failure
PAR	Peak-to-Average Ratio
SMD	Surface Mounted Device
VBW	Video BandWidth
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 11. Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF8G24LS-150V_8G24LS-150GV v.2	20140224	Objective data sheet	-	BLF8G24LS-150V_ 8G24LS-150GV v.1
Modifications	 Section 1. 	2 on page 1: list item 4, c	changed 60 MHz to	o 70 MHz
	<u>Section 1.3 on page 1</u> : deleted W-CDMA			
	• <u>Table 4 on page 2</u> : table note updated			
	 <u>Table 6 on page 3</u>: added row V_{GSq} 			
	 <u>Section 7.2 on page 4</u>: section added 			
	<u>Section 7.3 on page 5</u> : section added			
	• Section 7.	4 on page 5: section add	ed	
	• Section 7.	5 on page 6: section add	ed	
BLF8G24LS-150V_8G24LS-150GV v.1	20131104	Objective data sheet	-	-

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Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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